

picosecond time stamping capability in fully monolithic highly granular silicon pixel detectors



funded by the H2020 ERC Advanced grant 884447

ROBERTO CARDELLA ON BEHALF OF THE MONOLITH TEAM.









- 1. Introduction to SiGe BiCMOS Technology
- 2. ATTRACT prototype without Gain Layer
 - 1. Efficiency and Time Resolution
- 3. MONOLITH ERC
 - 1. PicoAD concept
 - 2. PicoAD p0: Efficiency and Time Resolution
 - 3. Electronics development: TDC
- 4. Summary and outlook









SiGe BiCMOS Process





NPN SiGe HBT (depleted regions in light colors)

 $\Delta \phi_n$

n

Si

Emitter

SiGe HBT = BJT with Germanium as base material:

- -> higher doping in base possible
- -> thinner base
- \rightarrow reduced base resistance R_{h}

Grading of Ge doping in base:

- -> charge transport in base via drift
- —> reduced charge transit time in base
- -> high current gain β













Leading-edge technology: IHP SG13G2

130 nm process featuring SiGe HBT with

- Transistor transition frequency: f t = 0.3 THZ•
- DC Current gain: $\beta = 900$ ٠
- Delay gate: 1.8 ps ٠



microelectronics Leibniz-Institut für innovative Mikroelektronik



ROBERTO.CARDELLA@UNIGE.CH



Silicon Group at UniGe



Giuseppe lacobucci

 project P.I. System design



Didier Ferrere System integration

Laboratory test



Pierpaolo Valerio

 Lead chip design Digital electronics



Mateus Vicente System integration · Laboratory test



Yana Gurimskaya Radiation tolerance · Laboratory test



Stefano Zambito · Laboratory test

Stéphane Débieux









Antonio Picardi Chip design Laboratory Test













Yannick Favre

Board design

RO system

Lorenzo Paolozzi

Analog electronics

System integration

Magdalena Munker

· Laboratory test

Sensor design

· Laboratory test

Roberto Cardella

Analog electronics

Sensor design

Fulvio Martinelli

Chip design

Sergio Gonzalez-Sevilla

Sensor design







Main research partners:

Marzio Nessi

Ivan Peric

KIT

CERN & UNIGE



Roberto Cardarelli INFN Rome Tor Vergata University of Geneva



Holger Rücker IHP Mikroelektronik



Mehmet Kaynak IHP Mikroelektronik



Bernd Heinemann IHP Mikroelektronik





FACULTY OF SCIENCE Department of Nuclear and Particle Physics

ROBERTO.CARDELLA@UNIGE.CH

24.02.22



ATTRACT prototype



 $100\mu m$ pitch hexagonal pixels - $25\mu m$ depletion



MPW submission in 2019 funded by H2020



Four Matrices

1. Active pixel

- Front end in pixel
- HBT preamp + driver (in pixel) + CMOS discriminator (outside pixel)
- 2. Active pixel v2
 - HBT preamp + CMOS discriminator
- 3. Limiting amplifier:
 - HBT preamp + HBT limiting amplifier
- 4. Double threshold:

• HBT preamp + two CMOS discriminators

<u>G. Iacobucci et al 2022 JINST 17 P02019</u>





FACULTY OF SCIENCE Department of Nuclear and Particle Physics

24.02.22

ROBERTO.CARDELLA@UNIGE.CH



ATTRACT prototype



100µm pitch hexagonal pixels - 25 µm depletion





UNDER TEST HERE

Analog Channels:

HBT preamp + two HBT Emitter Followers to 500Ω Resistance on pad. Out







MPW submission in 2019 funded by H2020



G. lacobucci et al 2022 JINST 17 P02019



MONOLITH

24.02.22







To get rid of the effect of the telescope precision, we used the bins of the area inside the red triangle, that represents the entire pixel area in the right proportions.













Efficiency measured at $HV = 120 V$				
I_{preamp} [μA]	7	20	50	150
Efficiency DUT0 [%]	96.1 ^{+1.4} -1.7	$99.75_{-0.17}^{+0.12}$	99.94 ^{+0.03} -0.05	$99.91^{+0.05}_{-0.08}$
Efficiency DUT1 [%]	$98.4_{-0.4}^{+0.3}$	$99.45\substack{+0.2 \\ -0.2}$	$99.86\substack{+0.05 \\ -0.07}$	$99.78\substack{+0.08 \\ -0.11}$













ATTRACT prototype – Time Stamping





$$\sigma_t = \frac{\sigma_{TOA0-TOA1}}{\sqrt{2}} = (36.4 \pm 0.8) \text{ps}$$
 without gain structure



FACULTY OF SCIENCE Department of Nuclear and Particle Physics

MONOLITH



MONOLITH ERC project



5 year ERC project to develop a monolithic silicon sensor able to measure precisely the 3D spatial position of charged particles while providing at the same time **picosecond time resolution**.







Exlabilished by the European Commission

H2020 ERC Advanced grant 884447, July 2020 - June 2025 ENNA CONFERENCE OF INSTRUMENTAT



FACULTY OF SCIENCE Department of Nuclear and Particle Physics









Placement of gain layer deep inside sensor:

De-correlation from pixel implant size/geometry —> high pixel granularity possible (*spatial precision*) Only small fraction of charge gets amplified —> reduced Landau charge fluctuations (*timing precision*)

Picosecond Avalanche Detector (PicoAD): EU Patent EP18207008.6







PicoAD prototype p0













 e^{-}/h^{+} Generation





FACULTY OF SCIENCE Department of Nuclear and Particle Physics

24.02.22

ROBERTO.CARDELLA@UNIGE.CH









e⁻ /h⁺ Generation

Electrict Field -> Drift transport





FACULTY OF SCIENCE Department of Nuclear and Particle Physics







VIENNA CONFERENCE OF INSTRUMENTATIO

24.02.22



PicoAD – Gain Characterization





- Clear difference between wafer 6 and wafer 9 for the same dose (under investigation)
- Dose 1 almost no holes gain, use for normalization to get electron gain







PicoAD – Gain Characterization





Wafer9 shows gain between 15 and 20 for temperatures between +20 and -20 degrees

Consistent behaviour of the 3 samples

The curve is expected to saturate: Hypothesis -> Space Charges reduce electron gain





FACULTY OF SCIENCE Department of Nuclear and Particle Physics

22

24

e gain



PicoAD p0 vs p0 NO GAIN





Reduced depletion thickness and still better results







PicoAD - Time Stamping







TDC Monolith





Picosecond TDC test chip



Integrated in MONOLITH p1 Prototype: under test Improved TDC version back from foundry in April 2022.







Outlook and Summary



